

MBM1200E17F

Silicon N-channel IGBT 1700V F version

FEATURES

- * Soft switching behavior & low conduction loss :
Soft low-injection punch-through with trench gate IGBT
- * Low driving power due to low input capacitance advanced trench gate.
- * Low noise due to ultra soft fast recovery diode.
- * High thermal fatigue durability.

ABSOLUTE MAXIMUM RATINGS (T_C=25°C)

Item	Symbol	Unit	MBM1200E17F
Collector Emitter Voltage	V _{CEs}	V	1,700
Gate Emitter Voltage	V _{GES}	V	±20
Collector Current	DC	I _C	1,200
	1ms	I _{CRM}	2,400
Forward Current	DC	I _F	1,200
	1ms	I _{FRM}	2,400
Junction Temperature	T _{vj op}	°C	-50 ~ +150
Storage Temperature	T _{stg}	°C	-55 ~ +125
Isolation Voltage	V _{ISO}	V _{RMS}	4,000(AC 1 minute)
Screw Torque	Terminals (M4/M8)	-	2/15 (1)
	Mounting (M6)	-	6 (2)

Notes: (1) Recommended Value 1.8±0.2/15⁺⁰₋₃N·m (2) Recommended Value 5.5±0.5N·m

ELECTRICAL CHARACTERISTICS

Item	Symbol	Unit	Min.	Typ.	Max.	Test Conditions	
Collector Emitter Cut-Off Current	I _{CEs}	mA	-	-	10	V _{CE} =1,700V, V _{GE} =0V, T _{vj} =25°C	
Gate Emitter Leakage Current	I _{GES}	nA	-500	-	+500	V _{CE} =1,700V, V _{GE} =0V, T _{vj} =150°C	
Collector Emitter Saturation Voltage	V _{CEsat}	V	-	2.0	-	I _C =1,200A, V _{GE} =15V, T _{vj} =25°C	
			-	2.4	-	I _C =1,200A, V _{GE} =15V, T _{vj} =150°C	
Gate Emitter Threshold Voltage	V _{GE(th)}	V	4.1	5.5	7.1	V _{CE} =10V, I _C =120mA, T _{vj} =25°C	
Input Capacitance	C _{ies}	nF	-	63	-	V _{CE} =10V, V _{GE} =0V, f=100kHz, T _{vj} =25°C	
Internal Gate Resistance	R _{G(int)}	Ω	-	4	-	V _{CE} =10V, V _{GE} =0V, f=100kHz, T _{vj} =25°C	
Turn On Delay Time	t _{d(on)}	μs	-	0.74	1.7	V _{CC} =900V, I _C =1,200A	
Rise Time	t _r		-	0.26	0.8	L _S =100nH (3)	
Turn Off Delay Time	t _{d(off)}		-	1.9	3.0	R _G (on/off)=2.7/4.7Ω (3)	
Fall Time	t _f		-	1.6	3.0	V _{GE} =±15V, T _{vj} =150°C	
Peak Forward Voltage Drop	V _F	V	-	2.0	-	I _F =1,200A, V _{GE} =0V, T _{vj} =25°C	
			-	2.3	-	I _F =1,200A, V _{GE} =0V, T _{vj} =150°C	
Reverse Recovery Time	t _{rr}	μs	-	0.65	1.5	V _{CC} =900V, I _C =1,200A	
Turn On Loss	E _{on}	J/P	-	0.31	-	L _S =100nH (3)	
Turn Off Loss	E _{off}	J/P	-	0.93	-	R _G (on/off)=2.7/4.7Ω (3)	
Reverse Recovery Loss	E _{rr}	J/P	-	0.44	-	V _{GE} =±15V, T _{vj} =150°C	
Short Circuit Pulse Width	t _{sc}	μs	10	-	-	V _{CC} =1,000V, L _S =80nH, C _{ge} =120nF R _G (on/off)=8.2/82Ω, V _{GE} =±15V, T _{vj} =150°C	
Stray inductance module	L _{SCE}	nH	-	21	-	per 1 arm	
Thermal Impedance	IGBT	R _{th(f-c)}	K/W	-	-	0.022	Junction to case
	FWD	R _{th(f-c)}		-	-	0.033	
Contact Thermal Impedance	R _{th(c-f)}	K/W	-	0.008	-	Case to fin	

Notes:(3) L_S and R_G are the test condition's values for evaluation of the switching times, not recommended value.

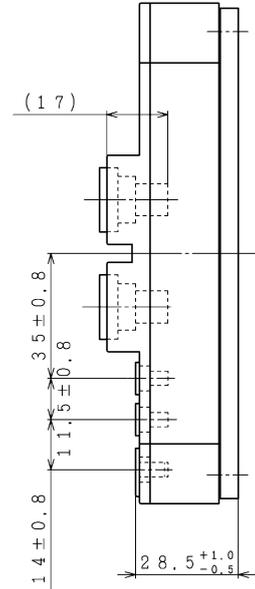
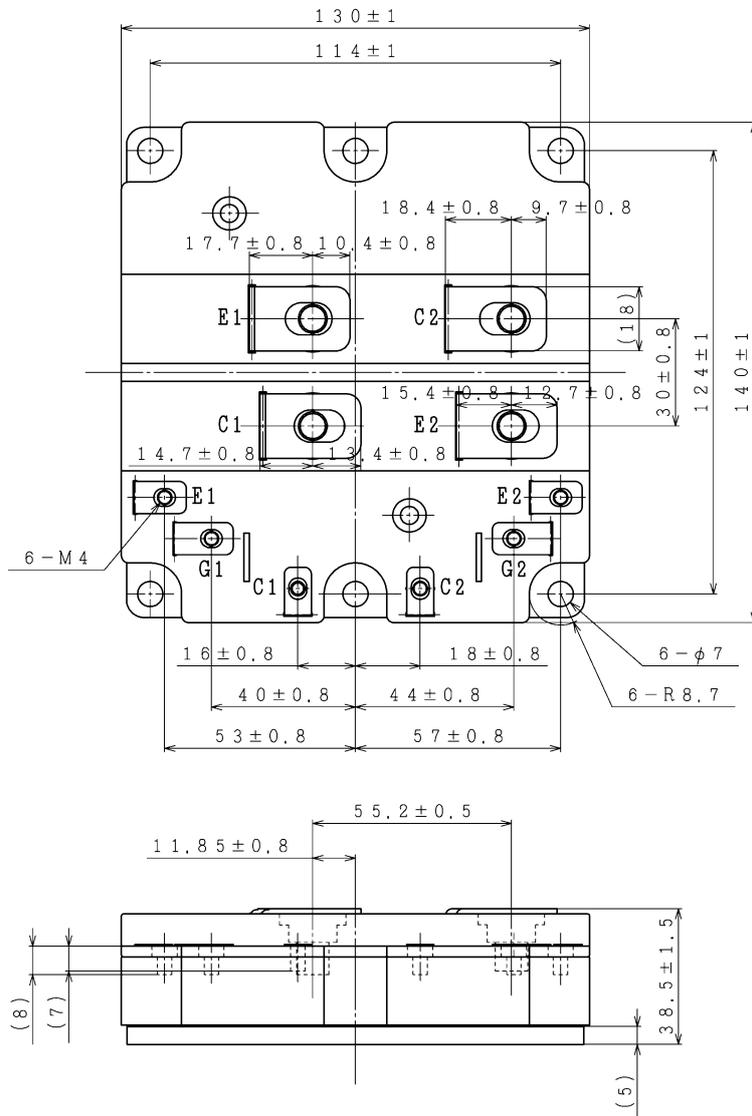
Please, determine the suitable R_G value after the measurement of switching waveforms (overshoot voltage, etc.) with appliance mounted.

- * Please contact our representatives at order.
- * For improvement, specifications are subject to change without notice.
- * For actual application, please confirm this spec sheet is the newest revision.
- * ELECTRICAL CHARACTERISTIC items shown in above table are according to IEC 60747-2 and IEC 60747-9.

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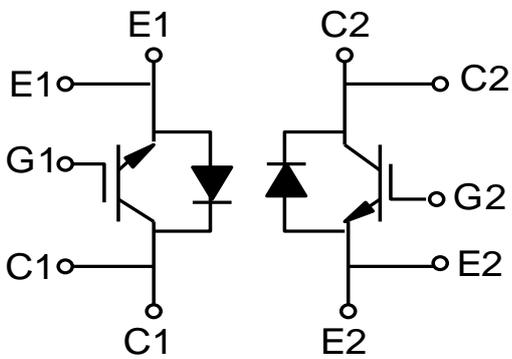
OUTLINE DRAWING

Unit in mm

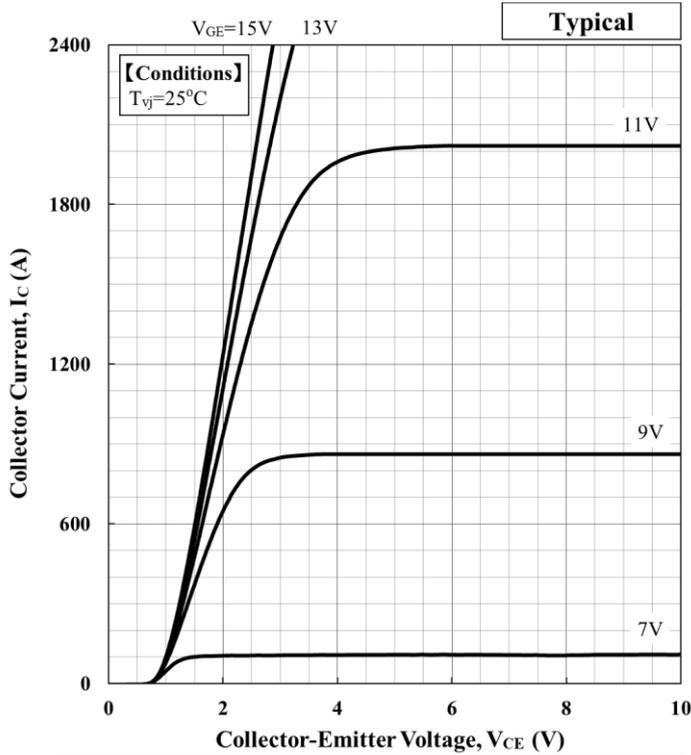


Weight: 900g

CIRCUIT DIAGRAM



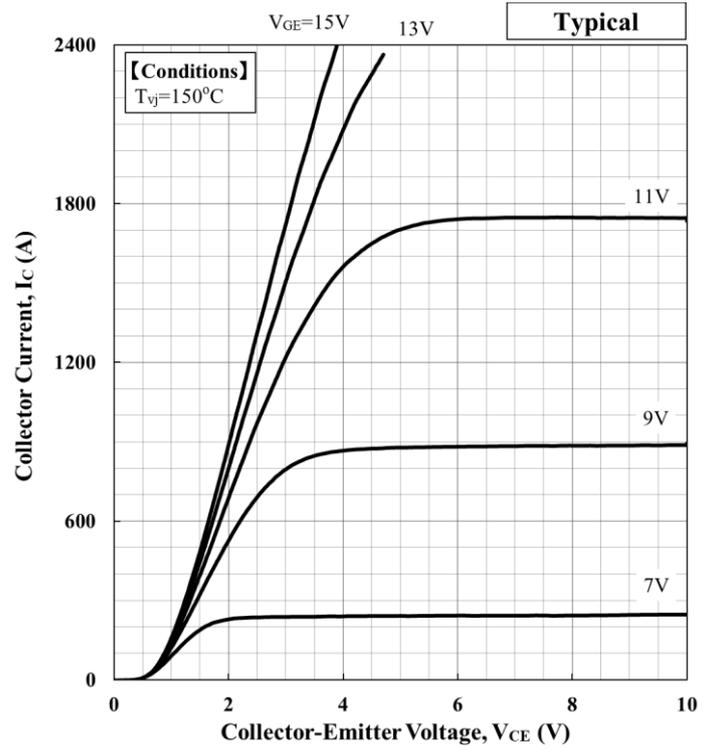
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$$V_{CE}(sat)[V] = a_3 \cdot |I_c|^3 + a_2 \cdot |I_c|^2 + a_1 \cdot |I_c| + a_0$$

Temp.[°C]	V _{GE} [V]	a ₃	a ₂	a ₁	a ₀
25	15	5.98.E-11	-2.79.E-07	1.14.E-03	9.01.E-01

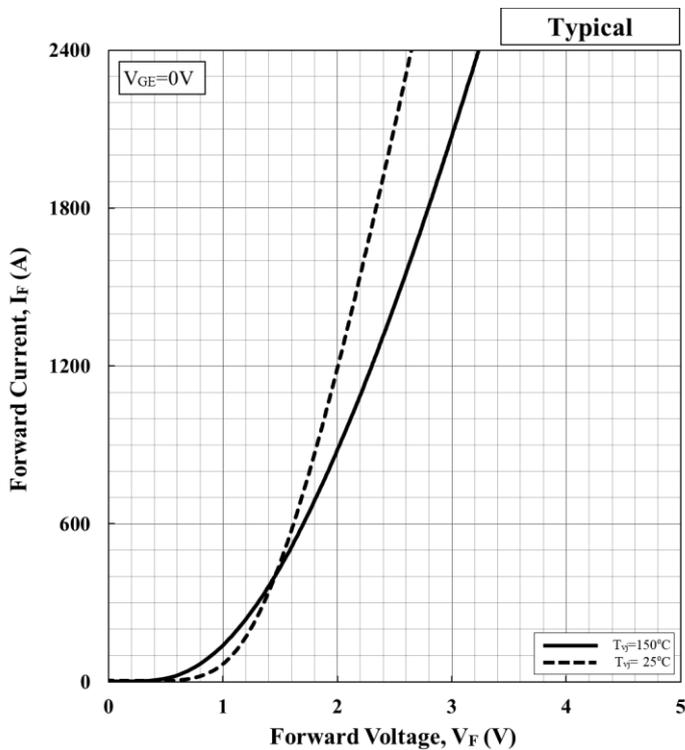
Collector Current vs. Collector Emitter Voltage



$$V_{CE}(sat)[V] = a_3 \cdot |I_c|^3 + a_2 \cdot |I_c|^2 + a_1 \cdot |I_c| + a_0$$

Temp.[°C]	V _{GE} [V]	a ₃	a ₂	a ₁	a ₀
150	15	1.13.E-10	-4.48.E-07	1.75.E-03	7.29.E-01

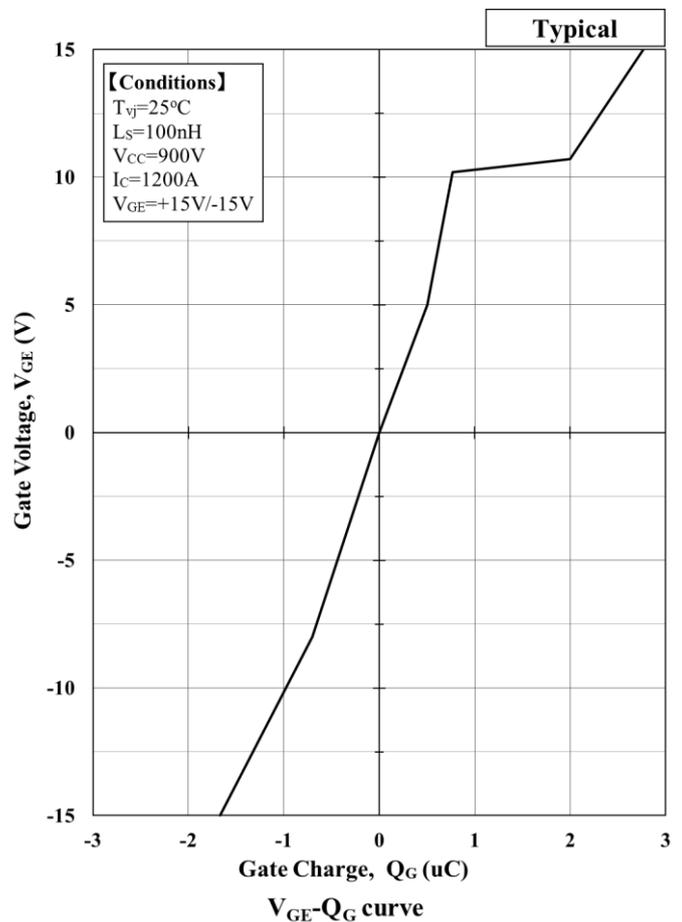
Collector Current vs. Collector Emitter Voltage



$$V_F[V] = a_3 \cdot |I_F|^3 + a_2 \cdot |I_F|^2 + a_1 \cdot |I_F| + a_0$$

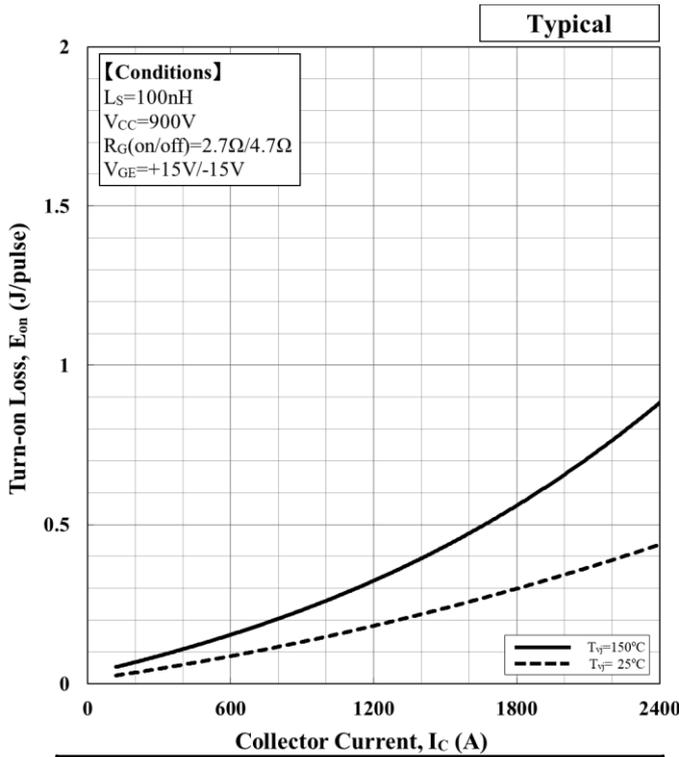
Temp.[°C]	a ₃	a ₂	a ₁	a ₀
25	8.98.E-11	-4.62.E-07	1.29.E-03	9.79.E-01
150	1.25.E-10	-6.62.E-07	1.91.E-03	7.55.E-01

Forward Voltage of free-wheeling diode



Gate Voltage, V_{GE} (V)
Gate Charge, Q_G (uC)
V_{GE}-Q_G curve

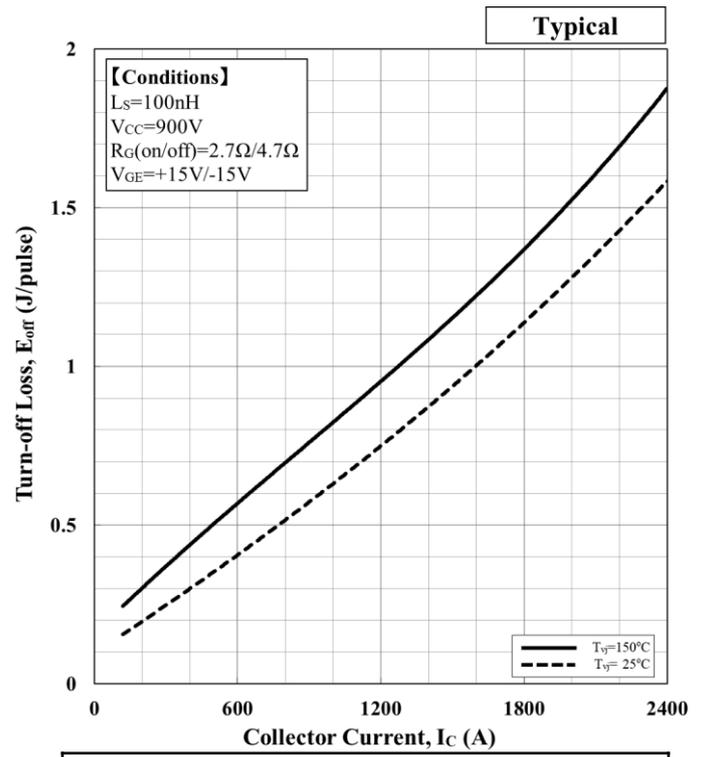
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$$E [J] = a_3 \cdot |I_c|^3 + a_2 \cdot |I_c|^2 + a_1 \cdot |I_c| + a_0$$

Temp.[°C]	a_3	a_2	a_1	a_0
25	-1.01.E-13	3.03.E-08	1.04.E-04	1.36.E-02
150	1.58.E-11	3.57.E-08	1.79.E-04	3.11.E-02

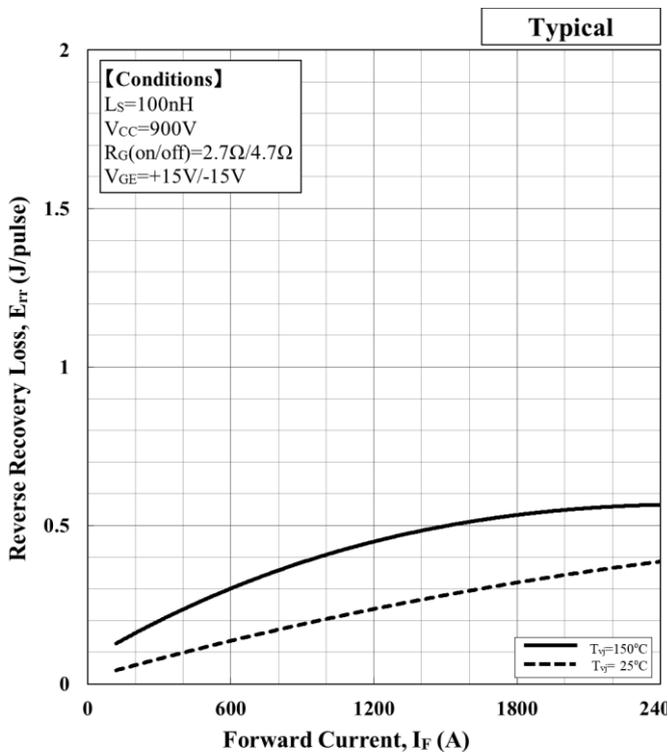
Turn-on loss vs. Collector current



$$E [J] = a_3 \cdot |I_c|^3 + a_2 \cdot |I_c|^2 + a_1 \cdot |I_c| + a_0$$

Temp.[°C]	a_3	a_2	a_1	a_0
25	9.07.E-12	3.06.E-08	4.94.E-04	9.68.E-02
150	7.04.E-12	2.72.E-08	6.14.E-04	1.47.E-01

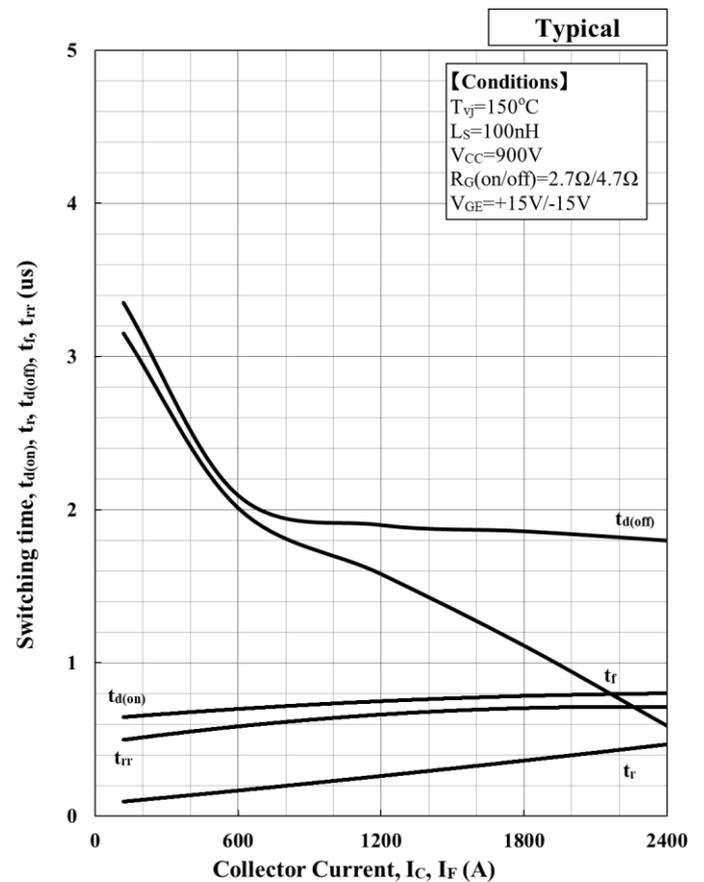
Turn-off loss vs. Collector current



$$E [J] = a_3 \cdot |I_f|^3 + a_2 \cdot |I_f|^2 + a_1 \cdot |I_f| + a_0$$

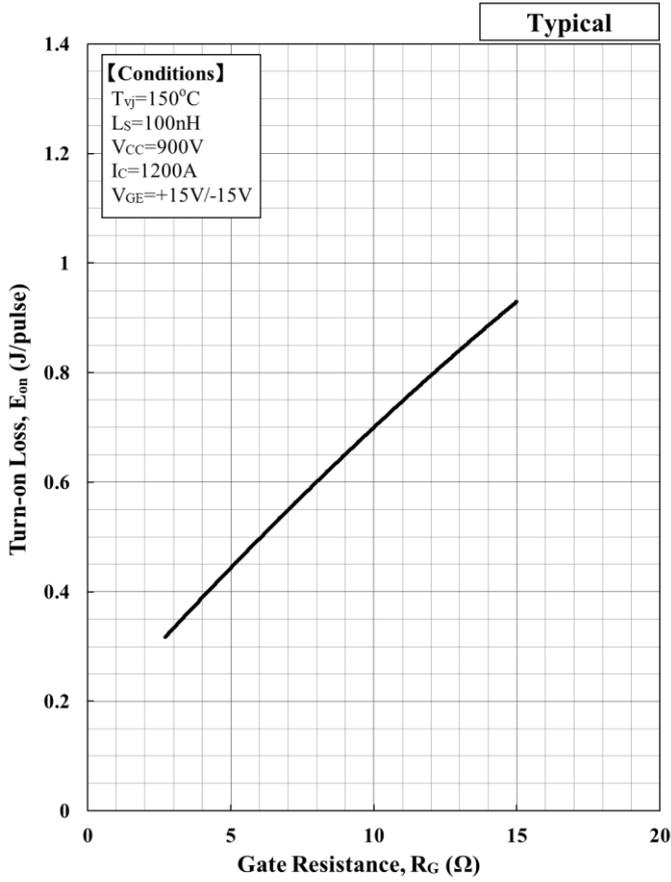
Temp.[°C]	a_3	a_2	a_1	a_0
25	0.00.E+00	-2.38.E-08	2.10.E-04	1.84.E-02
150	9.90.E-12	-1.25.E-07	4.47.E-04	7.61.E-02

Recovery loss vs. Forward current

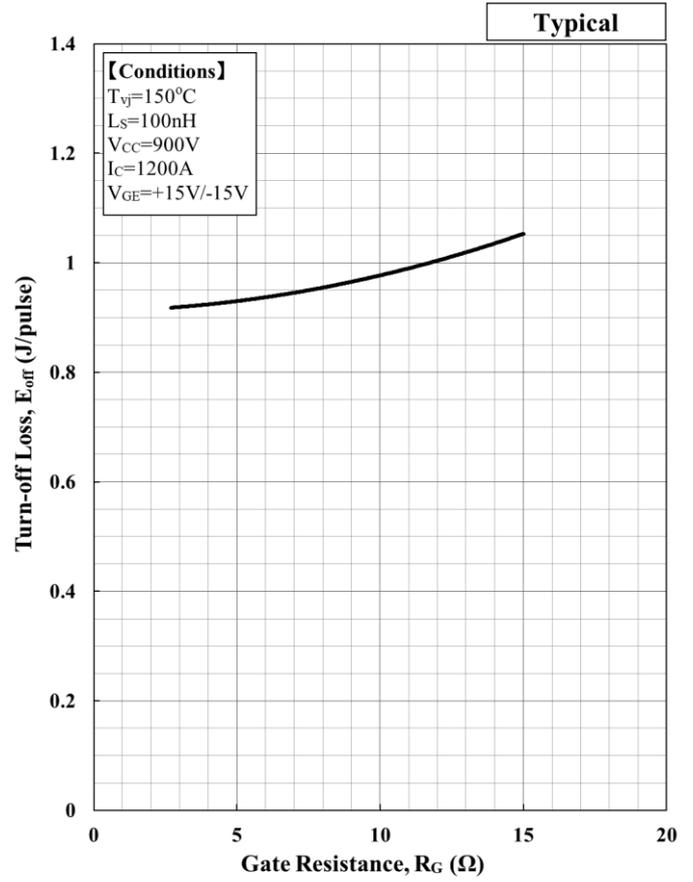


Switching time vs. Collector Current

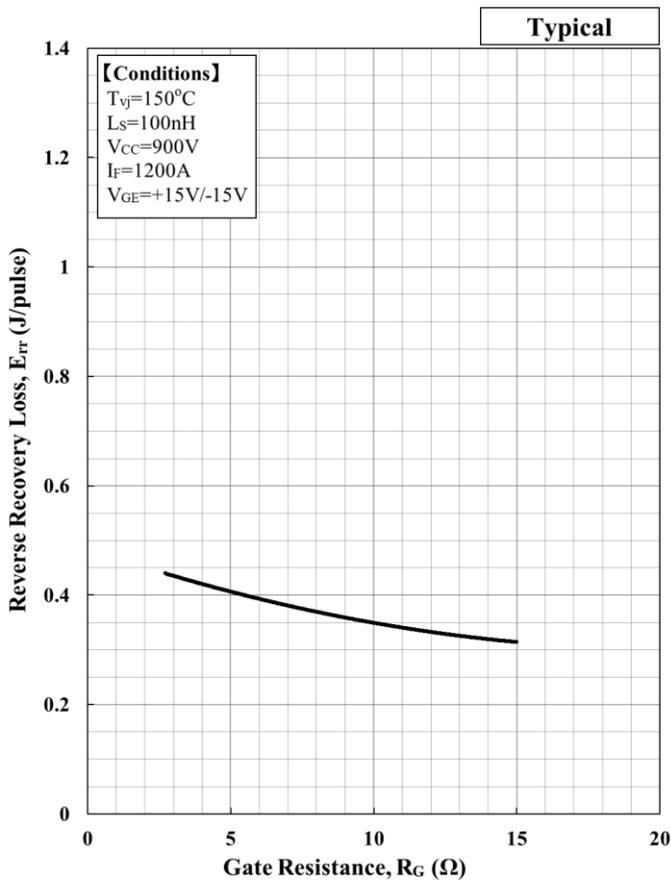
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Turn-on loss vs. Gate Resistance

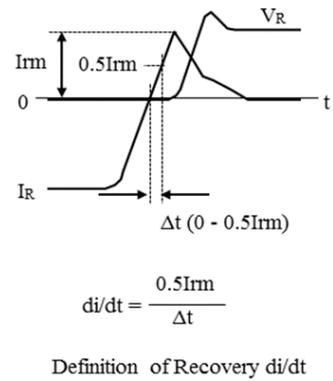
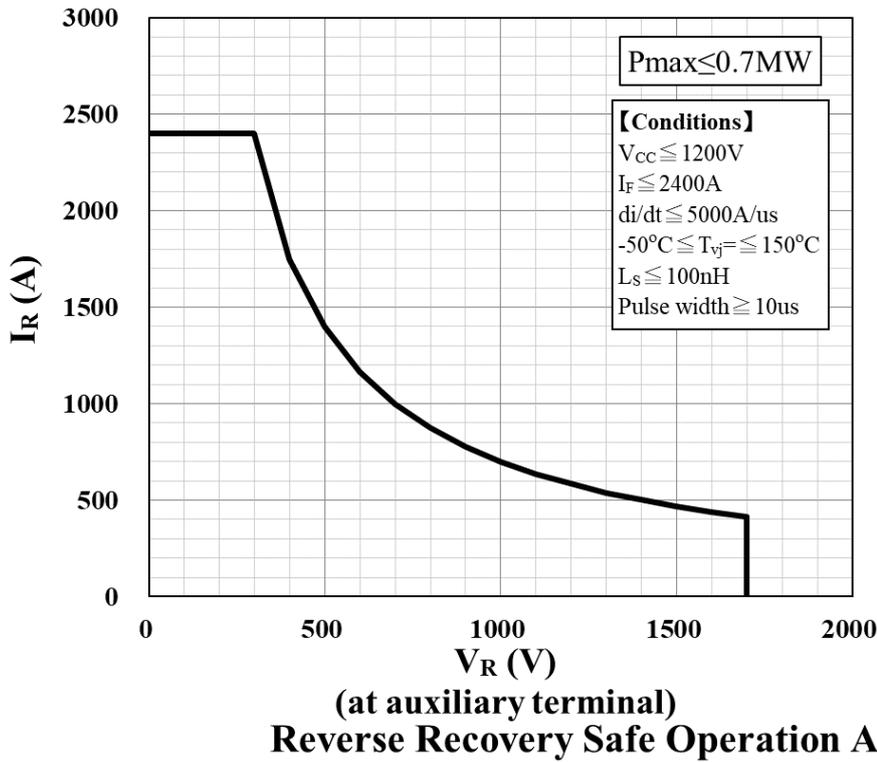
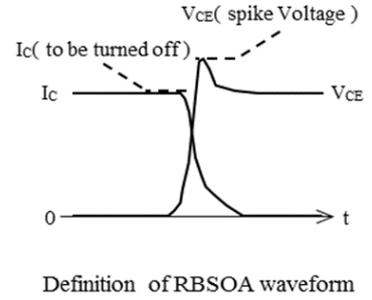
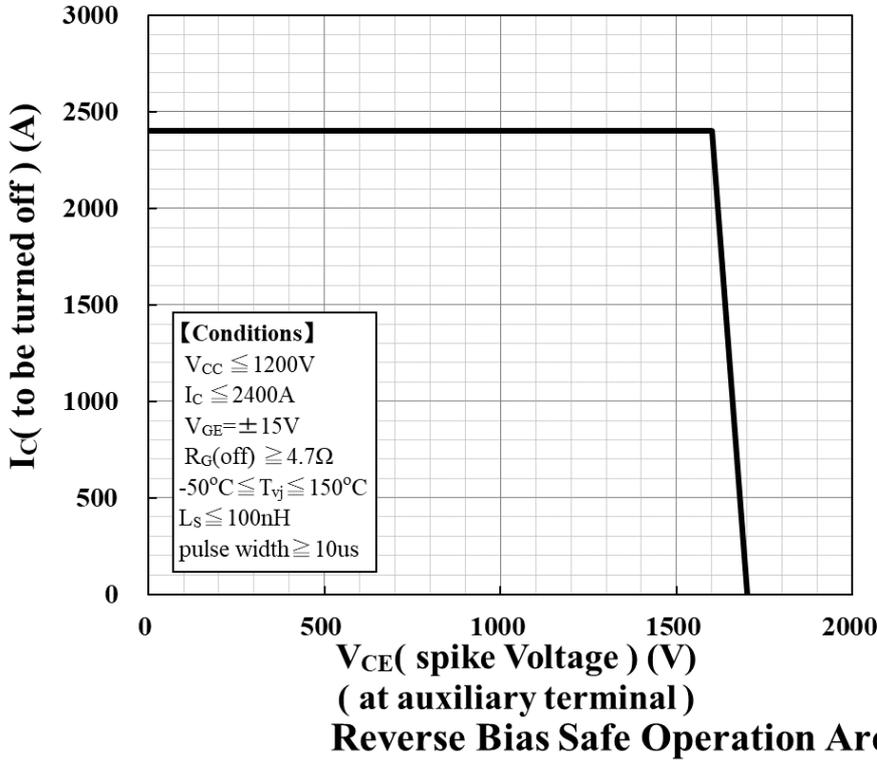


Turn-off loss vs. Gate Resistance

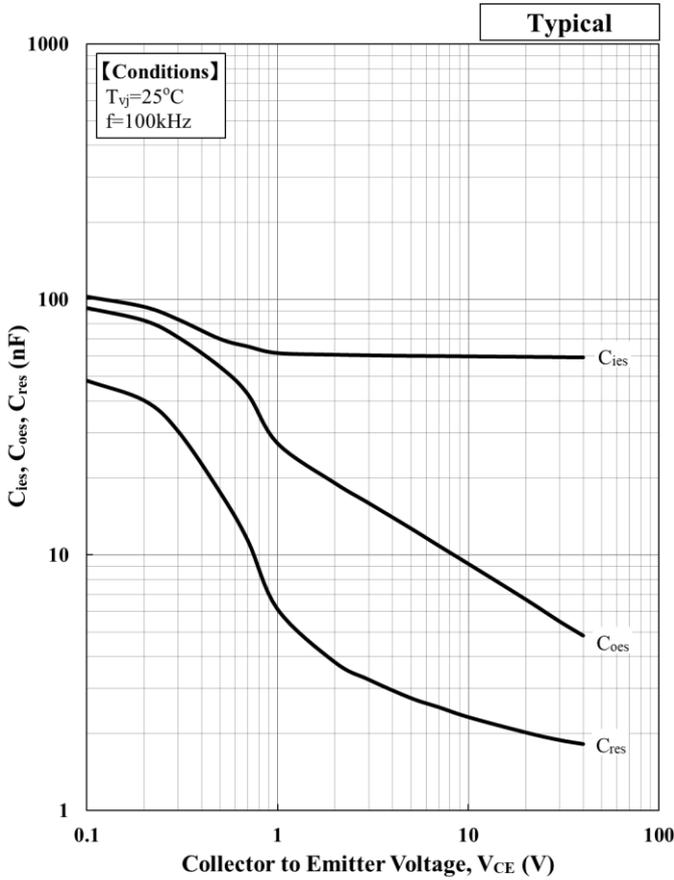


Reverse Recovery loss vs. Gate Resistance

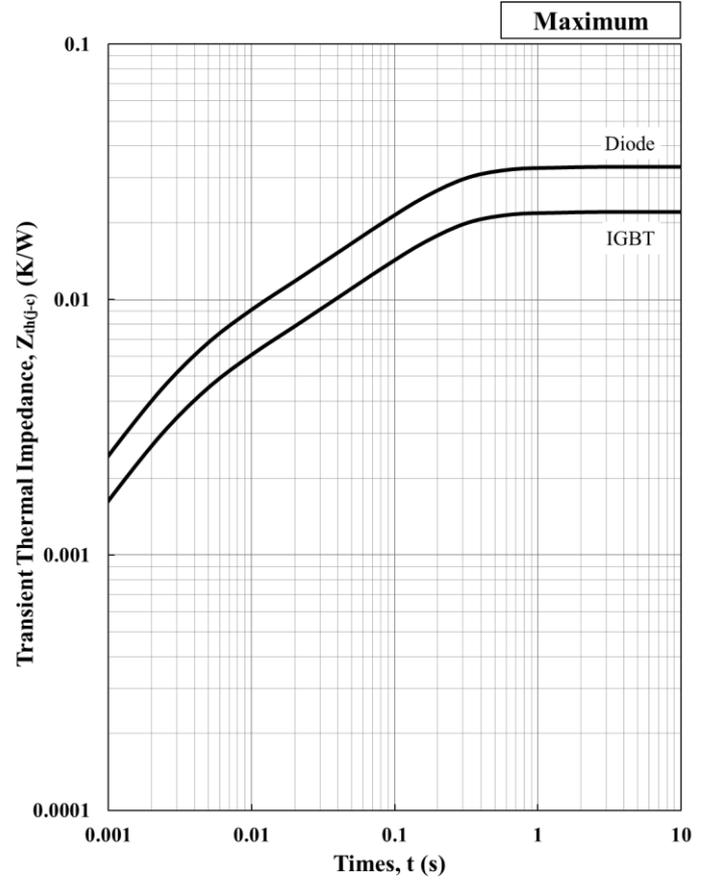
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Capacitance vs. Collector to Emitter Voltage



Transient Thermal Impedance Curve

Foster model lumped circuit constant

n	1	2	3	4
R th, IGBT [n]	1.42E-02	3.66E-03	3.68E-03	5.04E-04
C th, IGBT [n]	1.15E+01	6.79E+00	8.53E-01	1.07E+00
R th, Diode [n]	2.11E-02	5.75E-03	5.38E-03	7.73E-04
C th, Diode [n]	7.70E+00	4.32E+00	5.84E-01	6.98E-01

Cauer model lumped circuit constant

n	1	2	3	4
R th, IGBT [n]	2.60E-03	3.37E-03	7.35E-03	8.68E-03
C th, IGBT [n]	4.27E-01	5.71E-01	4.25E+00	1.18E+01
R th, Diode [n]	3.83E-03	5.08E-03	1.11E-02	1.30E-02
C th, Diode [n]	2.85E-01	3.89E-01	2.74E+00	8.01E+00

Material declaration

Please note the following materials are contained in the product, in order to keep characteristic and reliability level.

Material	Contained part
Lead (Pb) and its compounds	Solder

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Minebea POWER SEMICONDUCTORS

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1. Since mishandling of semiconductor devices may cause malfunctions, please be sure to read "Precautions for Safe Use and Notices" in the individual brochure before use.
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